



ZHCS501B -NOVEMBER 2011-REVISED FEBRUARY 2012

120V 启动电压、4A 峰值电流的高频高端/低端驱动器

查询样品: UCC27210, UCC27211

特性

- 可驱动两个高端/低端配置中的 N通道 MOSFET并 具有独立输入
- 最大启动电压: 120V DC
- 4A 吸收、4A 供电输出电流
- 0.9-Ω 上拉/下拉电阻
- 输入引脚电压范围 -10 V 至 20 V 并且独立于电源 电压之外
- TTL 或者伪-CMOS 兼容输入版本
- 8-V 至 17-V VDD 运行范围, (最大值 20 V ABS)
- 7.2 ns 上升和 5.5 ns 下降时间 (1000pF 负载 时)
- 快速传播延迟(典型值 18-ns)
- 2ns 延迟匹配
- 用于高端和低端驱动器的对称欠压闭锁功能
- 采用全工业标准 (SOIC-8, PowerPAD™ SOIC-8, 4-mm x 4-mm SON-8 和 4-mm x 4-mm SON-10)封装
- 额定温度范围 -40 至 140°C

应用范围

- 针对电信、数据通信和商业市场的电源
- 半桥式和全桥式转换器
- 推•拉转换器
- 高电压同步降压型转换器
- 两开关正激式转换器
- 有源箝位正激式转换器
- D类音频放大器

说明

UCC27210 和 UCC27211 驱动器是基于流行的 UCC27200 和 UCC27201 MOSFET 驱动器设计而成 的,但相对于之前的产品,此两款器件的性能有很大提 升。 峰值输出上拉和下拉电流已经增加至 4-A 源电 流/4-A 吸收电流,而上拉/下拉电阻也已经减少到 0.9 Ω ,这样的话,在MOSFET的米勒效应平台转换期间, 能够在保证最小切换损失的前提下驱动大功率 MOSFET。 此输入结构现在能直接处理 10 VDC, 这 增加了耐用性并且也在无需使用整流二极管的情况下实 现到栅极驱动变压器的直接接口连接。 此输入也与电 源电压无关并且最大额定电压为 20-V。



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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

说明 (续)

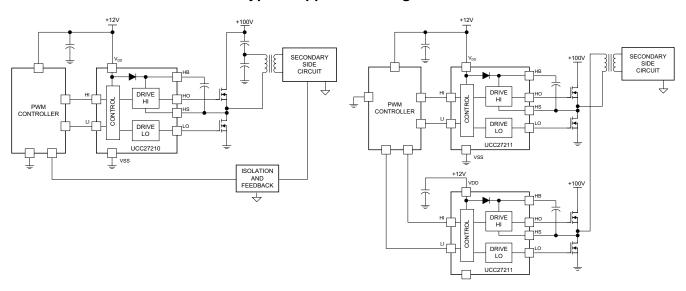
UCC27210/1 的开关结点 (HS 引脚) 能够处理最大-18 V电压,这样就保护高端通道不受由寄生电感和杂散电容引起的固有负电压带来的损害。 UCC27210 (伪-CMOS输入) 和 UCC27211 (TTL 输入) 已经增加了滞后时间,这样就实现了到具有增强抗噪性能的模拟或者数字PWM控制器的接口连接。

低端和高端栅极驱动器是独立控制的,它们之间打开和关闭的匹配时间为 2 ns。

片载额定 120-V自举二极管省去了对外部分立式二极管的需要。 为高端和低端驱动器提供了欠压闭锁功能,如果驱动电压低于规定的门限,则提供对称的打开/关闭性能并将输出强制设为低电平。

这两款器件均采用 8 引脚 SOIC(D)、PowerPad™ SOIC-8 (DDA)、4-mm x 4-mm SON-8(DRM) 和 SON-10 (DPR) 封装。

Typical Application Diagrams



ORDERING INFORMATION (1)

	INPUT		PACKAGED	DEVICES ⁽¹⁾	
TEMPERATURE RANGE T _A = T _J	COMPATIBILITY	SOIC-8 (D) ⁽²⁾	PowerPAD™ SOIC-8 (DDA) ⁽²⁾	SON-8 (DRM) ⁽³⁾	SON-10 (DPR) ⁽⁴⁾
-40°C to 140°C	Pseudo CMOS	UCC27210D	UCC27210DDA	UCC27210DRM	UCC27210DPR
-40 C to 140 C	TTL	UCC27211D	UCC27211DDA	UCC27211DRM	UCC27211DPR

- (1) These products are packaged in Lead (Pb)-Free and green lead finish of PdNiAu which is compatible with MSL level 1 at 255°C to 260°C peak reflow temperature to be compatible with either lead free or Sn/Pb soldering operations.
- (2) D (SOIC-8) and DDA (Power Pad™ SOIC-8) packages are available taped and reeled. Add R suffix to device type (e.g. UCC27210ADR/UCC27211ADR) to order quantities of 2,500 devices per reel.
- (3) DRM (SON-8) package comes either in a small reel of 250 pieces as part number UCC27210ADRMT/UCC27211ADRMT, or larger reels of 3000 pieces as part number UCC27210ADRMR/UCC27211ADRMR.
- (4) DPR (SON-10) package comes either in a small reel of 250 pieces as part number UCC27210ADPRT/UCC27211ADPRT, or large reels of 3000 pieces as part number UCC27210ADPRR/UCC27211ADPRR.



ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
Supply voltage range, V _{DD} ⁽¹⁾ , V _{HB} - \	Supply voltage range, V _{DD} ⁽¹⁾ , V _{HB} - V _{HS}			
Input voltages on LI and HI, V _{LI} , V _{HI}	-10	20		
Output valtage as I O V	DC	-0.3	V _{DD} + 0.3	
Output voltage on LO, V _{LO}	Repetitive pulse <100 ns ⁽²⁾	-2	V _{DD} + 0.3	
Outrot valtage en LIO V	DC	V _{HS} - 0.3	V _{HB} + 0.3	V
Output voltage on HO, V _{HO}	Repetitive pulse <100 ns ⁽²⁾	V _{HS} - 2	V _{HB} + 0.3	
Voltage on HS, V _{HS}	DC	-1	115	
	Repetitive pulse <100 ns ⁽²⁾	-18	115	
Voltage on HB, V _{HB}		-0.3	120	
	Human Body Model (HBM)		2	
ESD	Field Induced Charged Device Model (FICDM)		1	kV
Operating virtual junction temperatur	-40	150		
Storage temperature, T _{STG}	-65	150	°C	
Lead temperature (soldering, 10 sec		300		

⁽¹⁾ All voltages are with respect to VSS unless otherwise noted. Currents are positive into, negative out of the specified terminal.

RECOMMENDED OPERATING CONDITIONS

all voltages are with respect to V_{SS} ; currents are positive into and negative out of the specified terminal. $-40^{\circ}\text{C} < T_J = T_A < 140^{\circ}\text{C}$ (unless otherwise noted)

PARAMETER	MIN	TYP	MAX	UNIT
Supply voltage range, V _{DD} , V _{HB} -V _{HS}	8	12	17	
Voltage on HS, V _{HS}	-1		105	
Voltage on HS, V _{HS} (repetitive pulse <100 ns)	-15		110	V
Voltage on HB, V _{HB}	V _{HS} +8, V _{DD} -1		V _{HS} +17, 115	
Voltage slew rate on HS			50	V/ns
Operating junction temperature range	-40		140	°C

⁽²⁾ Verified at bench characterization.



THERMAL INFORMATION

		UCC272		
	THERMAL METRIC	D	DDA	UNITS
		8 PINS	8 PINS	
θ_{JA}	Junction-to-ambient thermal resistance ⁽²⁾	111.8	37.7	
θ_{JCtop}	Junction-to-case (top) thermal resistance (3)	56.9	47.2	
θ_{JB}	Junction-to-board thermal resistance (4)	53.0	9.6	°C/W
ΨЈТ	Junction-to-top characterization parameter ⁽⁵⁾	7.8	2.8	C/VV
ΨЈВ	Junction-to-board characterization parameter (6)	52.3	9.4	
θ_{JCbot}	Junction-to-case (bottom) thermal resistance (7)	n/a	3.6	

- (1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.
- (2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
- (3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
- (4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
- (5) The junction-to-top characterization parameter, ψ_{JT}, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{IA}, using a procedure described in JESD51-2a (sections 6 and 7).
- (6) The junction-to-board characterization parameter, ψ_{JB}, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA}, using a procedure described in JESD51-2a (sections 6 and 7).
- (7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

THERMAL INFORMATION

		UCC27			
	THERMAL METRIC	DRM	DPR	UNITS	
		8 PINS	10 PINS	1	
θ_{JA}	Junction-to-ambient thermal resistance ⁽²⁾	33.9	36.8		
θ_{JCtop}	Junction-to-case (top) thermal resistance (3)	33.2	36.0		
θ_{JB}	Junction-to-board thermal resistance (4)	11.4	14.0	2004	
ΨЈТ	Junction-to-top characterization parameter ⁽⁵⁾	0.4	0.3	°C/W	
Ψ_{JB}	Junction-to-board characterization parameter (6)	11.7	14.2		
θ_{JCbot}	Junction-to-case (bottom) thermal resistance (7)	2.3	3.4		

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- (2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
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- (7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.



ELECTRICAL CHARACTERISTICS

 $V_{DD} = V_{HB} = 12 \text{ V}, V_{HS} = V_{SS} = 0 \text{ V}, \text{ no load on LO or HO}, T_A = T_J = -40 ^{\circ}\text{C}$ to 140 $^{\circ}\text{C}$, (unless otherwise noted)

PARAM	IETER		TEST CONDITION	MIN	TYP	MAX	UNITS	
Supply	Currents							
I _{DD}	V _{DD} quiescent current		V(LI) = V(HI) = 0 V	0.05	0.085	0.17		
I _{DDO}	M	UCC27210	(500 111- 0 0	2.4	2.6	4.3		
	V _{DD} operating current	UCC27211	$f = 500 \text{ kHz}, C_{LOAD} = 0$	2.4	2.5	4.3	mA	
I _{HB}	Boot voltage quiescent curr	ent	V(LI) = V(HI) = 0 V	0.015	0.065	0.1		
I _{HBO}	Boot voltage operating curr	ent	f = 500 kHz, C _{LOAD} = 0	1.5	2.5	4		
I _{HBS}	HB to V _{SS} quiescent curren	t	V(HS) = V(HB) = 115 V		0.0005	0.13	μA	
I _{HBSO}	HB to V _{SS} operating curren	t	f = 500 kHz, C _{LOAD} = 0		0.07	0.9	mA	
Input								
V_{HIT}	Input voltage threshold			4.2	5.0	5.8		
V_{LIT}	Input voltage threshold		110027240	2.4	3.2	4.0	V	
V _{IHYS}	Input voltage hysteresis		UCC27210		1.8			
R _{IN}	Input pulldown resistance				102		kΩ	
V _{HIT}	Input voltage threshold			1.9	2.3	2.7	\/	
V_{LIT}	Input voltage threshold		110027244	1.3	1.6	1.9	V	
V_{IHYS}	Input voltage hysteresis		UCC27211		700		mV	
R _{IN}	Input pulldown resistance				68		kΩ	
Under-\	/oltage Lockout (UVLO)							
V_{DDR}	V _{DD} turn-on threshold			6.2	7.0	7.8		
$V_{\rm DDHYS}$	Hysteresis				0.5		V	
V_{HBR}	V _{HB} turn-on threshold			5.6	6.7	7.9	V	
V_{HBHYS}	Hysteresis				1.1			
Bootstr	ap Diode							
V_{F}	Low-current forward voltage	e	$I_{VDD-HB} = 100 \mu A$		0.65	0.8	V	
V_{FI}	High-current forward voltag	e	I _{VDD-HB} = 100 mA		0.85	0.95	V	
R_D	Dynamic resistance, ΔVF/Δ	I	I_{VDD-HB} = 100 mA and 80 mA	0.3	0.5	0.85	Ω	
LO Gate	e Driver							
V_{LOL}	Low-level output voltage		I _{LO} = 100 mA	0.05	0.09	0.15	V	
V_{LOH}	High level output voltage		I_{LO} = -100 mA, V_{LOH} = V_{DD} - V_{LO}	0.1	0.16	0.27	V	
	Peak pull-up current ⁽¹⁾		$V_{LO} = 0 V$		3.7		۸	
	Peak pull-down current ⁽¹⁾		V _{LO} = 12 V		4.5		Α	
HO GAT	TE Driver							
V_{HOL}	Low-level output voltage		I _{HO} = 100 mA	0.05	0.09	0.15	\/	
V_{HOH}	High-level output voltage		I_{HO} = -100 mA, V_{HOH} = V_{HB} - V_{HO}	0.1	0.16	0.27	V	
	Peak pull-up current ⁽¹⁾				3.7		^	
	Peak pull-down current ⁽¹⁾		V _{HO} = 12 V		4.5		A	

⁽¹⁾ Ensured by design.

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ELECTRICAL CHARACTERISTICS (continued)

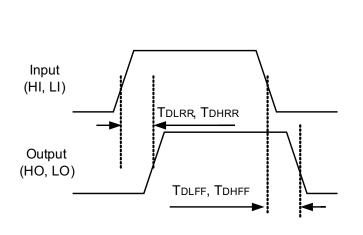
 $V_{DD} = V_{HB} = 12 \text{ V}, V_{HS} = V_{SS} = 0 \text{ V}, \text{ no load on LO or HO}, T_A = T_J = -40 ^{\circ}\text{C}$ to 140 $^{\circ}\text{C}$, (unless otherwise noted)

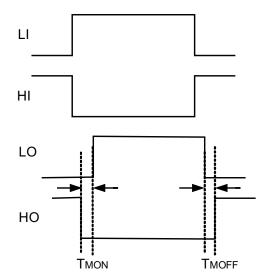
PARAN	METER		TEST CONDITION	MIN	TYP	MAX	UNITS	
Switchi	ing Parameters: Propagation	n Delays						
T _{DLFF}	V _{LI} falling to V _{LO} falling			17	21	37		
T _{DHFF}	V _{HI} falling to V _{HO} falling		110007040 0	17	21	37		
T _{DLRR}	V _{LI} rising to V _{LO} rising		UCC27210, C _{LOAD} = 0	18	24	46		
T _{DHRR}	V _{HI} rising to V _{HO} rising			18	24	46		
T _{DLFF}	V _{LI} falling to V _{LO} falling			10	17	30	ns	
T _{DHFF}	V _{HI} falling to V _{HO} falling		LICC27211 C = 0	10	17	30		
T _{DLRR}	V _{LI} rising to V _{LO} rising		UCC27211, C _{LOAD} = 0	10	18	40		
T_{DHRR}	V _{HI} rising to V _{HO} rising			10	18	40		
Switchi	ing Parameters: Delay Matc	hing						
т	From HO OFF to LO ON		$T_J = 25^{\circ}C$		3	11	20	
T _{MON}	FIGHT HO OFF TO LO ON	UCC27210	$T_J = -40$ °C to 140°C		3	14	ns	
т	F	00027210	$T_J = 25^{\circ}C$		3	11	no	
T _{MOFF}	From LO OFF to HO ON		$T_J = -40$ °C to 140°C		3	14	ns	
T	From HO OFF to LO ON		$T_J = 25^{\circ}C$		2	9.5	ns	
T _{MON}	TIONITIO OTT TO LO ON	UCC27211	$T_J = -40$ °C to 140°C		2	14	113	
T	From LO OFF to HO ON	00027211	$T_J = 25^{\circ}C$	2		9.5	ns	
T _{MOFF}	TIONI LO OTT TOTTO ON		$T_J = -40$ °C to 140°C		2	14	115	
Switchi	ing Parameters: Output Rise	and Fall Time	-					
t_R	LO rise time		C _{LOAD} = 1000 pF, from 10% to 90%		7.2			
t_R	HO rise time		CLOAD = 1000 pr , 110111 10 % to 90 %		7.2		ns	
t _F	LO fall time		$C_{LOAD} = 1000 \text{ pF, from } 90\% \text{ to } 10\%$		5.5		115	
t _F	HO fall time		OLOAD = 1000 pr , 110111 90 % to 10 %		5.5			
t_R	LO, HO		$C_{LOAD} = 0.1 \mu F$, (3 V to 9 V)		0.36	0.6	μs	
t _F	LO, HO		$C_{LOAD} = 0.1 \mu F$, (9 V to 3 V)		0.15	0.4	μδ	
Switchi	ing Parameters: Miscellaned	ous						
	Minimum input pulse width output	that changes the				50	ns	
	Bootstrap diode turn-off tim	e ⁽²⁾⁽³⁾	I _F = 20 mA, I _{REV} = 0.5 A ⁽⁴⁾		20			

 ⁽²⁾ Ensured by design.
 (3) I_F: Forward current applied to bootstrap diode, I_{REV}: Reverse current applied to bootstrap diode.
 (4) Typical values for T_A = 25°C.



Timing Diagrams

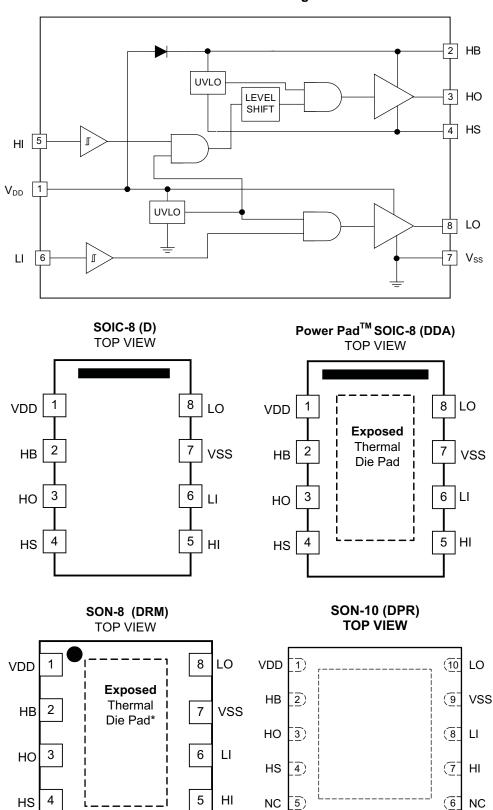






DEVICE INFORMATION

Functional Block Diagram





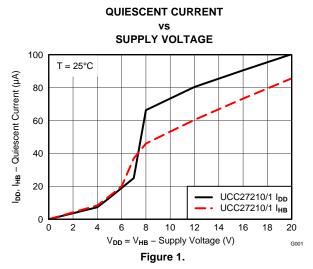
TERMINAL FUNCTIONS

DIN NAME	PI	N	DESCRIPTION				
PIN NAME D/DDA/DRM DPR		DPR	DESCRIPTION				
VDD	1	1	Positive supply to the lower-gate driver. De-couple this pin to V_{SS} (GND). Typical decoupling capacitor range is 0.22 μF to 1.0 μF .				
НВ	2	2	High-side bootstrap supply. The bootstrap diode is on-chip but the external bootstrap capacitor is required. Connect positive side of the bootstrap capacitor to this pin. Typical range of HB bypass capacitor is 0.022 µF to 0.1 µF. The capacitor value is dependant on the gate charge of the high-side MOSFET and should also be selected based on speed and ripple criteria				
НО	3	3	High-side output. Connect to the gate of the high-side power MOSFET.				
HS	4	4	High-side source connection. Connect to source of high-side power MOSFET. Connect the negative side of bootstrap capacitor to this pin.				
HI	5	7	High-side input.				
LI	6	8	Low-side input.				
VSS	7	9	Negative supply terminal for the device which is generally grounded.				
LO	8	10	Low-side output. Connect to the gate of the low-side power MOSFET.				
N/C	-	5/6	Not Connected.				
PowerPAD™ (1)	Pad	Pad	Utilized on the DDA, DRM and DPR packages only. Electrically referenced to V _{SS} (GND). Connect to a large thermal mass trace or GND plane to dramatically improve thermal performance.				

⁽¹⁾ The PowerPAD™ is not directly connected to any leads of the package. However it is electrically and thermally connected to the substrate which is the ground of the device.

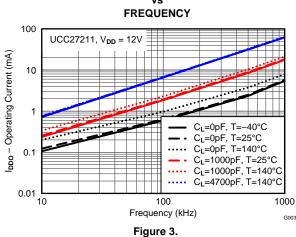


TYPICAL CHARACTERISTICS



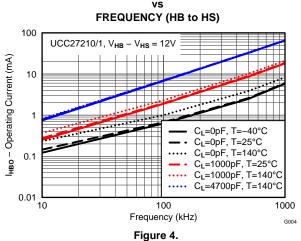
UCC27210 IDD OPERATING CURRENT FREQUENCY 100 UCC27210, V_{DD} = 12V Ippo - Operating Current (mA) 10 C_L=0pF, T=25°C C_L=0pF, T=140°C 0.1 C_L=1000pF, T=25°C C_L=1000pF, T=140°C C_L=4700pF, T=140°C 0.01 10 100 1000 Frequency (kHz) G002

UCC27211 IDD OPERATING CURRENT

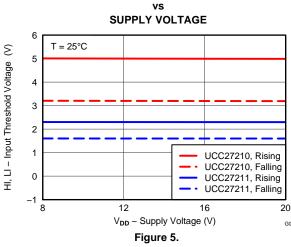


BOOT VOLTAGE OPERATING CURRENT

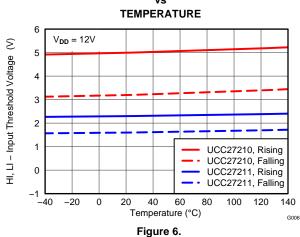
Figure 2.



UCC27210/11 INPUT THRESHOLD



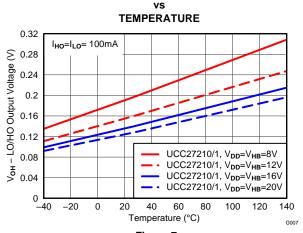
UCC27210/11 INPUT THRESHOLDS





TYPICAL CHARACTERISTICS (continued)

LO AND HO HIGH LEVEL OUTPUT VOLTAGE



LO AND HO LOW LEVEL OUTPUT VOLTAGE

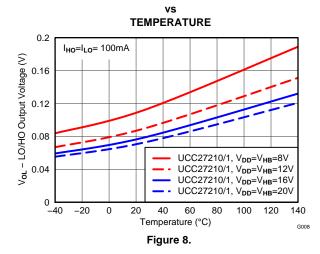
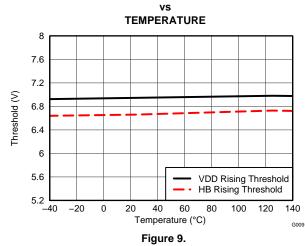
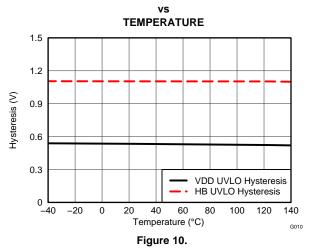


Figure 7.

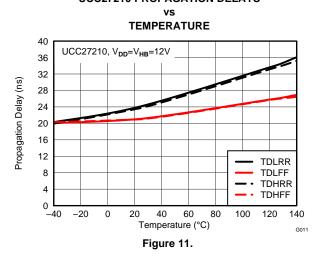
UNDERVOLTAGE LOCKOUT THRESHOLD



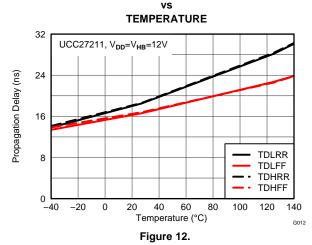
UNDERVOLTAGE LOCKOUT THRESHOLD HYSTERESIS



UCC27210 PROPAGATION DELAYS



UCC27211 PROPAGATION DELAYS



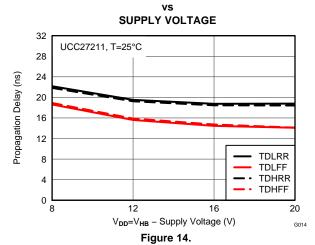


TYPICAL CHARACTERISTICS (continued)

UCC27210 PROPAGATION DELAYS

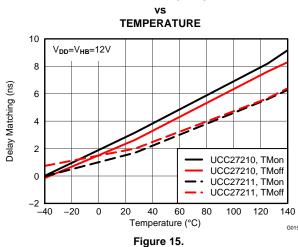
SUPPLY VOLTAGE 32 UCC27210, T=25°C 28 Propagation Delay (ns) 24 20 16 12 TDLRR 8 TDLFF TDHRR 4 **TDHFF** 0 8 20 V_{DD}=V_{HB} - Supply Voltage (V) G012

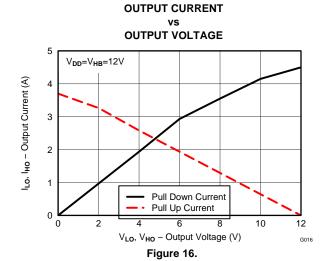
UCC27211 PROPAGATION DELAYS



DELAY MATCHING

Figure 13.





. .gu.o .c



TYPICAL CHARACTERISTICS (continued) DIODE CURRENT

G017

DIODE VOLTAGE 100 10 10 0.01 0.001 500 550 600 650 700 750 800 850

Figure 17.

Diode Voltage (mV)

Figure 18.

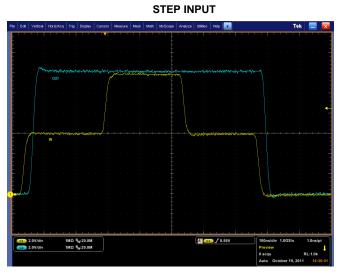




Figure 19.

Figure 20.



APPLICATION INFORMATION

Functional Description

The UCC27210/11 represent Texas Instruments' latest generation of high voltage gate drivers which are designed to drive both the high-side and low-side of N-Channel MOSFETs in a half-/full-bridge or synchronous buck configuration. The floating high-side driver is capable of operating with supply voltages of up to 120 V. This allows for N-Channel MOSFET control in half-bridge, full-bridge, push pull, two-switch forward and active clamp forward converters.

The UCC27210/11 feature 4-A source/sink capability, industry best-in-class switching characteristics and a host of other features listed in the table below. These features combine to ensure efficient, robust and reliable operation in high-frequency switching power circuits.

Table 1. UCC27210/11 Highlights

FEATURE	BENEFIT
4-A source and sink current with 0.9-Ω output resistance	High peak current ideal for driving large power MOSFETs with minimal power loss (fast-drive capability at Miller plateau)
Input pins (HI and LI) can directly handle -10 VDC up to 20 VDC	Increased robustness and ability to handle under/overshoot. Can interface directly to gate-drive transformers without having to use rectification diodes
120-V internal boot diode	Provides voltage margin to meet telecom 100-V surge requirements
Switch node (HS pin) able to handle -18 V maximum for 100 ns	Allows the high-side channel to have extra protection from inherent negative voltages caused parasitic inductance and stray capacitance.
Robust ESD circuitry to handle voltage spikes	Excellent immunity to large dV/dT conditions
18-ns propagation delay with 7.2-ns / 5.5-ns rise/fall Times	Best-in-class switching characteristics and extremely low-pulse transmission distortion
2-ns (typ) delay matching between channels	Avoids transformer volt-second offset in bridge
Symmetrical UVLO circuit	Ensures high-side and low-side shut down at the same time
CMOS optimized threshold or TTL optimized thresholds with increased hysteresis	Complementary to analog or digital PWM controllers. Increased hysteresis offers added noise immunity

In UCC27210/11, the high side and low side each have independent inputs which allow maximum flexibility of input control signals in the application. The boot diode for the high-side driver bias supply is internal to the UCC27210 and UCC27211. The UCC27210 is the Pseudo-CMOS compatible input version and the UCC27211 is the TTL or logic compatible version. The high-side driver is referenced to the switch node (HS) which is typically the source pin of the high-side MOSFET and drain pin of the low-side MOSFET. The low-side driver is referenced to V_{SS} which is typically ground. The functions contained are the input stages, UVLO protection, level shift, boot diode, and output driver stages.



Input Stages

The input stages provide the interface to the PWM output signals. The input impedance of the UCC27210 is 100 k Ω nominal and input capacitance is approximately 2 pF. The 100 k Ω is a pull-down resistance to V_{SS} (ground). The UCC27210 Pseudo-CMOS input structure has been designed to provide large hysteresis and at the same time to allows interfacing to a multitude of analog or digital PWM controllers. In some CMOS designs, the input thresholds are determined as a percentage of VDD. By doing so, the high-level input threshold can become unreasonably high and unusable. The UCC27210 recognizes the fact that VDD levels are trending downward and it therefore provides a rising threshold with 5.0 V (typ) and falling threshold with 3.2 V (typ). The input hysteresis of the UCC27210 is 1.8 V (typ).

The input stages of the UCC27211 have impedance of 70 k Ω nominal and input capacitance is approximately 2 pF. Pull-down resistance to V_{SS} (ground) is 70 k Ω . The logic level compatible input provides a rising threshold of 2.3 V and a falling threshold of 1.6 V.

Under Voltage Lockout (UVLO)

The bias supplies for the high-side and low-side drivers have UVLO protection. V_{DD} as well as V_{HB} to V_{HS} differential voltages are monitored. The V_{DD} UVLO disables both drivers when V_{DD} is below the specified threshold. The rising V_{DD} threshold is 7.0 V with 0.5-V hysteresis. The VHB UVLO disables only the high-side driver when the V_{HB} to V_{HS} differential voltage is below the specified threshold. The V_{HB} UVLO rising threshold is 6.7 V with 1.1-V hysteresis.

Level Shift

The level shift circuit is the interface from the high-side input to the high-side driver stage which is referenced to the switch node (HS). The level shift allows control of the HO output referenced to the HS pin and provides excellent delay matching with the low-side driver.

Boot Diode

The boot diode necessary to generate the high-side bias is included in the UCC27210/11 family of drivers. The diode anode is connected to V_{DD} and cathode connected to V_{HB} . With the V_{HB} capacitor connected to HB and the HS pins, the V_{HB} capacitor charge is refreshed every switching cycle when HS transitions to ground. The boot diode provides fast recovery times, low diode resistance, and voltage rating margin to allow for efficient and reliable operation.

Output Stages

The output stages are the interface to the power MOSFETs in the power train. High slew rate, low resistance and high peak current capability of both output drivers allow for efficient switching of the power MOSFETs. The low-side output stage is referenced from V_{DD} to V_{SS} and the high side is referenced from V_{HB} to V_{HS} .



Layout Recommendations

To improve the switching characteristics and efficiency of a design, the following layout rules should be followed.

- · Locate the driver as close as possible to the MOSFETs.
- Locate the V_{DD} and V_{HB} (bootstrap) capacitors as close as possible to the driver.
- Pay close attention to the GND trace. Use the thermal pad of the DDA and DRM package as GND by
 connecting it to the VSS pin (GND). The GND trace from the driver goes directly to the source of the
 MOSFET but should not be in the high current path of the MOSFET(S) drain or source current.
- Use similar rules for the HS node as for GND for the high-side driver.
- Use wide traces for LO and HO closely following the associated GND or HS traces. 60 to 100-mils width is preferable where possible.
- Use as least two or more vias if the driver outputs or SW node needs to be routed from one layer to another.
 For GND the number of vias needs to be a consideration of the thermal pad requirements as well as parasitic inductance.
- Avoid LI and HI (driver input) going close to the HS node or any other high dV/dT traces that can induce significant noise into the relatively high impedance leads.

Keep in mind that a poor layout can cause a significant drop in efficiency versus a good PCB layout and can even lead to decreased reliability of the whole system.

Example Component Placement

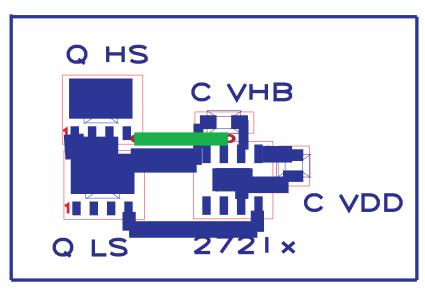


Figure 21. UCC27210/11 Component Placement

Additional References

These references and links to additional information may be found at www.ti.com

- Additional layout guidelines for PCB land patterns may be found in, QFN/SON PCB Attachment, Application Brief (Texas Instrument's Literature Number SLUA271)
- Additional thermal performance guidelines may be found in, *PowerPAD™ Thermally Enhanced Package Application Report*, Application Report (Texas Instrument's Literature Number SLMA002A)
- Additional thermal performance guidelines may be found in, PowerPAD™ Made Easy, Application Report (Texas Instrument's Literature Number SLMA004)







REVISION HISTORY

Changes from Revision A (November, 2011) to Revision B						
•	Changed ordering information notes to reflect corrected part number.	2				

www.ti.com 2-Oct-2024

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
UCC27210D	ACTIVE	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 140	27210	Samples
UCC27210DDA	ACTIVE	SO PowerPAD	DDA	8	75	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 140	27210	Samples
UCC27210DDAR	ACTIVE	SO PowerPAD	DDA	8	2500	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 140	27210	Samples
UCC27210DPRR	ACTIVE	WSON	DPR	10	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 140	UCC 27210	Samples
UCC27210DPRT	ACTIVE	WSON	DPR	10	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 140	UCC 27210	Samples
UCC27210DR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 140	27210	Samples
UCC27210DRMR	ACTIVE	VSON	DRM	8	3000	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 140	27210	Samples
UCC27210DRMT	ACTIVE	VSON	DRM	8	250	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 140	27210	Samples
UCC27211D	OBSOLETE	SOIC	D	8		TBD	Call TI	Call TI	-40 to 140	27211	
UCC27211DDA	OBSOLETE	SO PowerPAD	DDA	8		TBD	Call TI	Call TI	-40 to 140	27211	
UCC27211DDAR	ACTIVE	SO PowerPAD	DDA	8	2500	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 150	27211	Samples
UCC27211DPRR	ACTIVE	WSON	DPR	10	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 150	UCC 27211	Samples
UCC27211DPRT	OBSOLETE	E WSON	DPR	10		TBD	Call TI	Call TI	-40 to 140	UCC 27211	
UCC27211DR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 150	27211	Samples
UCC27211DRMR	ACTIVE	VSON	DRM	8	3000	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 150	27211	Samples
UCC27211DRMT	OBSOLETE	VSON	DRM	8		TBD	Call TI	Call TI	-40 to 140	27211	

⁽¹⁾ The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design. PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.



PACKAGE OPTION ADDENDUM

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(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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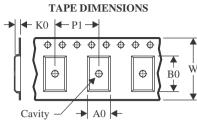
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TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

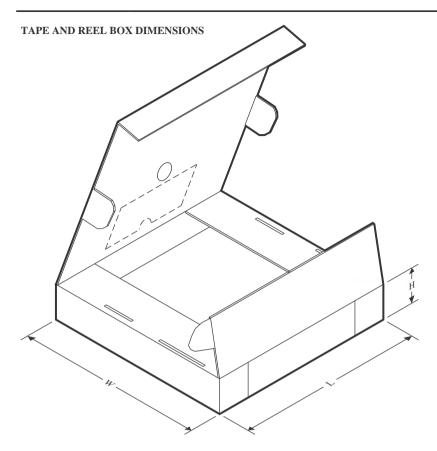


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
UCC27210DDAR	SO PowerPAD	DDA	8	2500	330.0	12.8	6.4	5.2	2.1	8.0	12.0	Q1
UCC27210DPRR	WSON	DPR	10	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
UCC27210DPRT	WSON	DPR	10	250	180.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
UCC27210DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
UCC27210DRMR	VSON	DRM	8	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
UCC27210DRMT	VSON	DRM	8	250	180.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
UCC27211DDAR	SO PowerPAD	DDA	8	2500	330.0	12.8	6.4	5.2	2.1	8.0	12.0	Q1
UCC27211DPRR	WSON	DPR	10	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
UCC27211DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
UCC27211DRMR	VSON	DRM	8	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2



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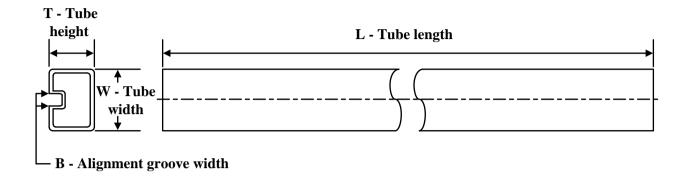
*All dimensions are nominal

7 til dillici sions are nominal							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
UCC27210DDAR	SO PowerPAD	DDA	8	2500	364.0	364.0	27.0
UCC27210DPRR	WSON	DPR	10	3000	346.0	346.0	33.0
UCC27210DPRT	WSON	DPR	10	250	182.0	182.0	20.0
UCC27210DR	SOIC	D	8	2500	356.0	356.0	35.0
UCC27210DRMR	VSON	DRM	8	3000	356.0	356.0	35.0
UCC27210DRMT	VSON	DRM	8	250	210.0	185.0	35.0
UCC27211DDAR	SO PowerPAD	DDA	8	2500	364.0	364.0	27.0
UCC27211DPRR	WSON	DPR	10	3000	346.0	346.0	33.0
UCC27211DR	SOIC	D	8	2500	356.0	356.0	35.0
UCC27211DRMR	VSON	DRM	8	3000	356.0	356.0	35.0

PACKAGE MATERIALS INFORMATION

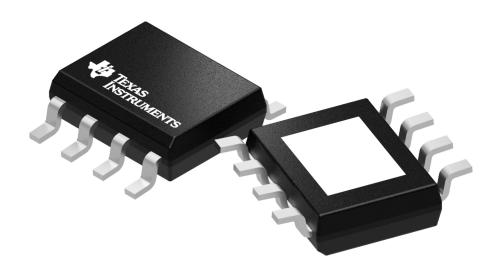
www.ti.com 25-Sep-2024

TUBE



*All dimensions are nominal

	Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
ĺ	UCC27210D	D	SOIC	8	75	506.6	8	3940	4.32
ĺ	UCC27210DDA	DDA	HSOIC	8	75	517	7.87	635	4.25



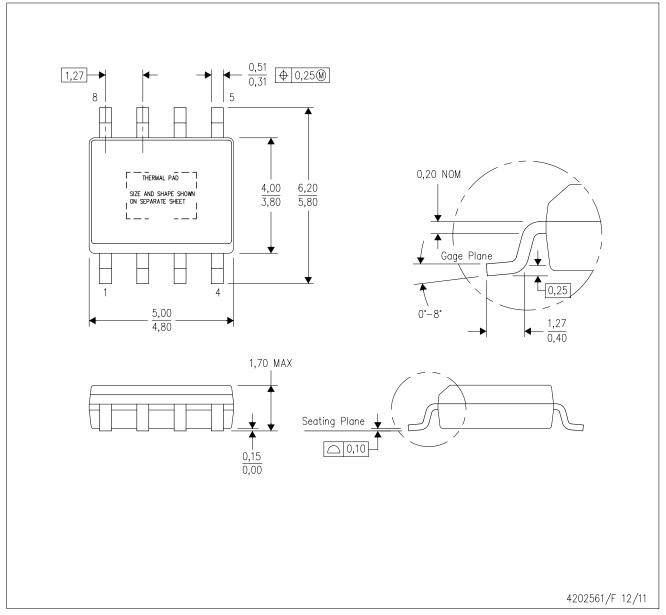
Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4202561/G



DDA (R-PDSO-G8)

PowerPAD ™ PLASTIC SMALL-OUTLINE



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 for information regarding recommended board layout. This document is available at www.ti.com http://www.ti.com.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- F. This package complies to JEDEC MS-012 variation BA

PowerPAD is a trademark of Texas Instruments.



DDA (R-PDSO-G8)

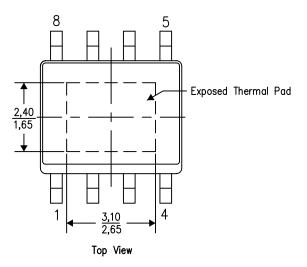
PowerPAD™ PLASTIC SMALL OUTLINE

THERMAL INFORMATION

This PowerPAD package incorporates an exposed thermal pad that is designed to be attached to a printed circuit board (PCB). The thermal pad must be soldered directly to the PCB. After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For additional information on the PowerPAD package and how to take advantage of its heat dissipating abilities, refer to Technical Brief, PowerPAD Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 and Application Brief, PowerPAD Made Easy, Texas Instruments Literature No. SLMA004. Both documents are available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Exposed Thermal Pad Dimensions

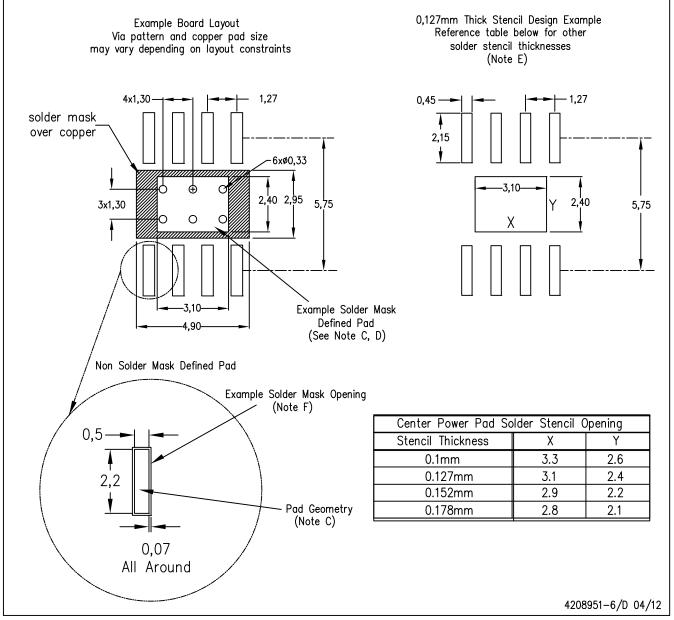
4206322-6/L 05/12

NOTE: A. All linear dimensions are in millimeters



DDA (R-PDSO-G8)

PowerPAD™ PLASTIC SMALL OUTLINE



NOTES:

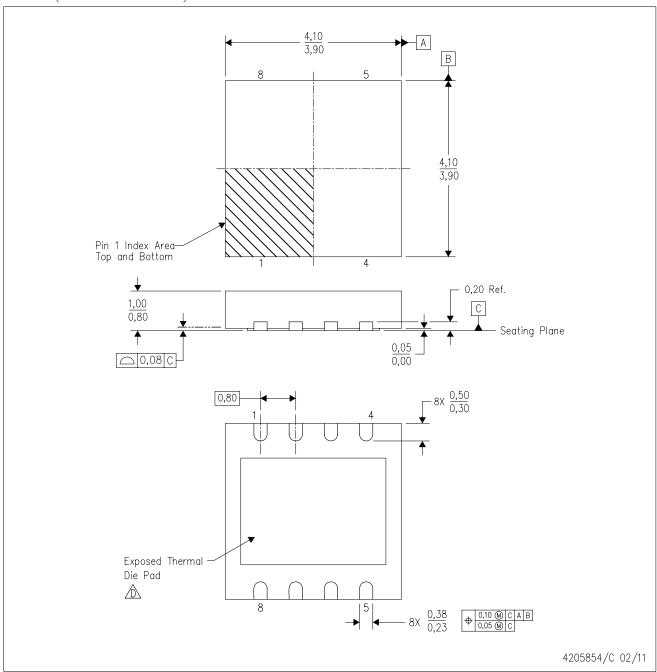
- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad Thermally Enhanced Package, Texas Instruments Literature No. SLMA002, SLMA004, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com http://www.ti.com. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.
- F. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

PowerPAD is a trademark of Texas Instruments.



DRM (S-PVSON-N8)

PLASTIC SMALL OUTLINE NO-LEAD



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.

- B. This drawing is subject to change without notice.
- C. SON (Small Outline No—Lead) package configuration.

 The package thermal pad must be soldered to the board for thermal and mechanical performance. See the Product Data Sheet for details regarding the exposed thermal pad dimensions.



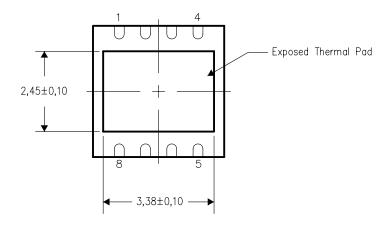


THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No—Lead (QFN) package and its advantages, refer to Application Report, Quad Flatpack No—Lead Logic Packages, Texas Instruments Literature No. SCBA017. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.

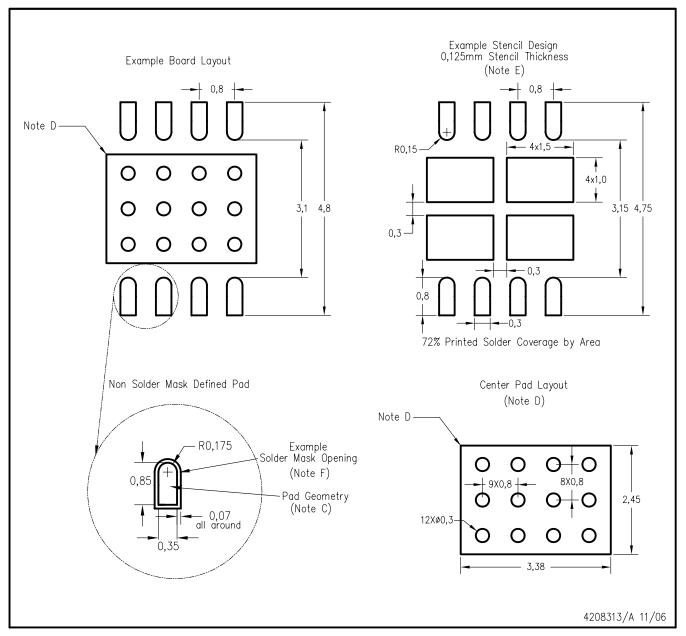


NOTE: All linear dimensions are in millimeters

Exposed Thermal Pad Dimensions

Bottom View

DRM (S-PDSO-N8)



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, QFN Packages, Texas Instruments Literature No. SCBA017, SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com https://www.ti.com.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for solder mask tolerances.





SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



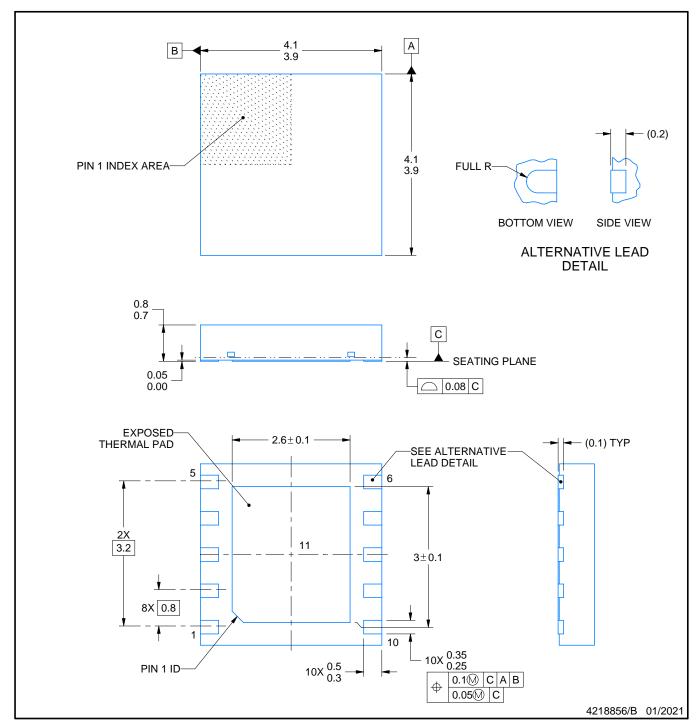
NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





PLASTIC SMALL OUTLINE - NO LEAD



NOTES:

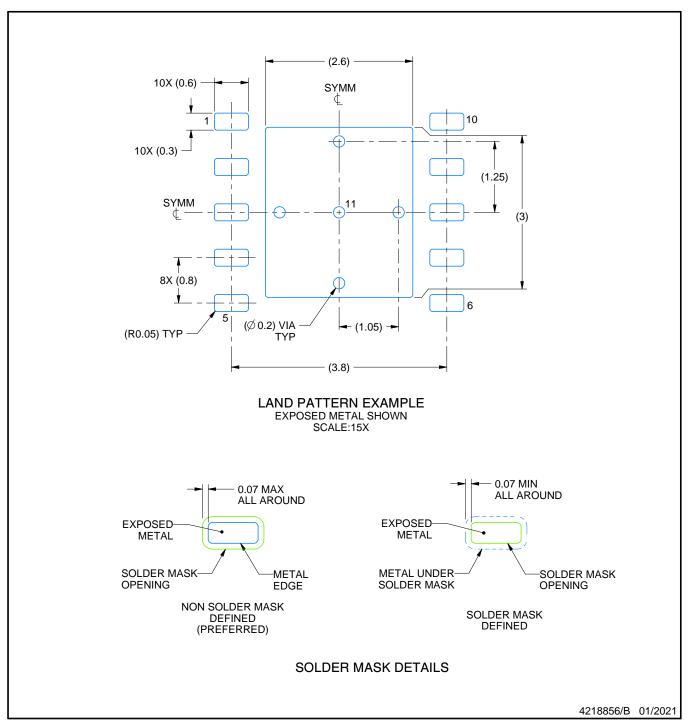
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC SMALL OUTLINE - NO LEAD

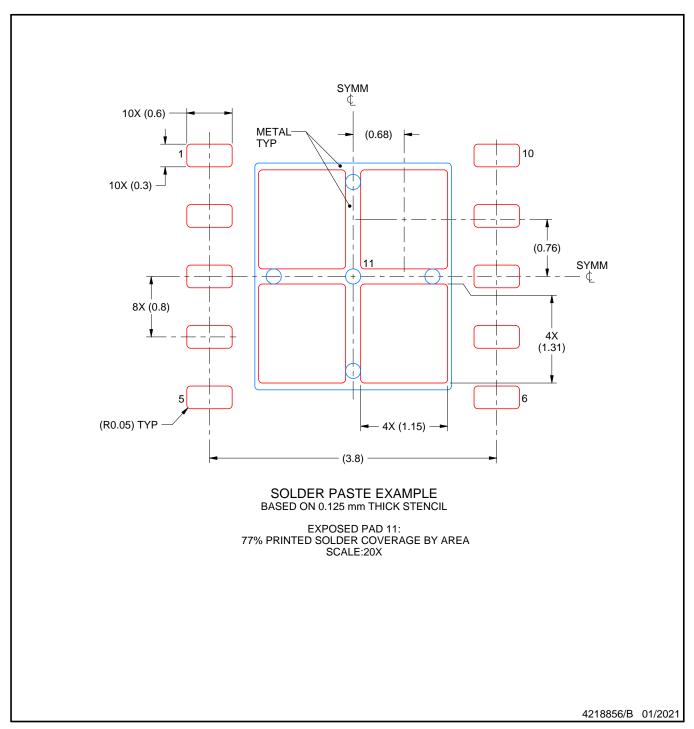


NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).



PLASTIC SMALL OUTLINE - NO LEAD



NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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